

FQP17P06-VB Datasheet

P-Channel 60-V (D-S) MOSFET

| PRODUCT SUMMARY | | |
|--|--------|----|
| V _{DS} | -60 | V |
| R _{DS(on)} V _{GS} = 10 V | 62 | mΩ |
| $R_{DS(on)}$ $V_{GS} = 4.5$ V | 74 | mΩ |
| I _D | -40 | А |
| Configuration | Single | |

FEATURES

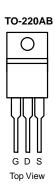
- TrenchFET[®] Power MOSFET
- 100 % UIS Tested

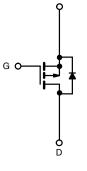
APPLICATIONS

Load Switch

S







P-Channel MOSFET

| ABSOLUTE MAXIMUM RATINGS $T_C = 2$ | 25 °C, unless othe | rwise noted | | |
|---|-------------------------|-----------------------------------|----------------|------|
| Parameter | | Symbol | Limit | Unit |
| Gate-Source Voltage | | V _{GS} | ± 20 | V |
| Continuous Drain Current ($T_1 = 175 \text{ °C}$) | T _C = 25 °C | L | -40 | |
| Continuous Drain Current (1) = 175 C) | T _C = 100 °C | I _D | -30 | |
| Pulsed Drain Current | | I _{DM} | - 90 | А |
| Continuing Source Current (Diode Conduction) | | ۱ _S | - 30 | |
| Avalanche Current | | I _{AS} | - 28 | |
| Single Pulse Avalanche Energy | L = 0.1 mH | E _{AS} | 7.2 | mJ |
| Maximum Dawar Dissinction | | 60 ^a | w | |
| Maximum Power Dissipation | T _A = 25 °C | ۲D | 2 ^b | vv |
| Operating Junction and Storage Temperature Range | · | T _J , T _{stg} | - 55 to 175 | °C |

| IERMAL RESISTANCE RATINGS | | | | | |
|----------------------------------|------------------------|-------------------|---------|---------|------|
| Parameter | | Symbol | Typical | Maximum | Unit |
| lun stime to Ambient | $t \le 10 \text{ sec}$ | | | | |
| Junction-to-Ambient ^b | Steady State | | 62 | 75 | °C/W |
| Junction-to-Case | | R _{thJC} | 5 | 6 | |

Notes:

a. See SOA curve for voltage derating.

b. Surface Mounted on 1" x 1" FR-4 boad.

| Parameter | Symbol | Test Conditions | Min | Typ ^a | Max | Unit |
|---|----------------------|---|-------|------------------|-------|------|
| Static | | 1 1 | | , ,, | | |
| Drain-Source Breakdown Voltage | V _{(BR)DSS} | $V_{GS} = 0 V, I_D = -250 \mu A$ | - 60 | | | |
| Gate Threshold Voltage | V _{GS(th)} | $V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$ | - 1.0 | | - 3.0 | V |
| Gate-Body Leakage | I _{GSS} | $V_{DS} = 0 V, V_{GS} = \pm 20 V$ | | | ± 100 | nA |
| | | $V_{DS} = -60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ | | | - 1 | |
| Zero Gate Voltage Drain Current | I _{DSS} | $V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$ | | | - 50 | μA |
| | | $V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 175 \text{ °C}$ | | | - 150 | - |
| On-State Drain Current ^b | I _{D(on)} | V _{DS} = - 5 V, V _{GS} = - 10 V | - 10 | | | А |
| | | V _{GS} = - 10 V, I _D = - 5 A | | 62 | | |
| | r | V_{GS} = - 10 V, I _D = - 5 A, T _J = 125 °C | | 80 | | |
| Drain-Source On-State Resistance ^b | r _{DS(on)} | V_{GS} = - 10 V, I _D = - 5 A, T _J = 175 °C | | 110 | | mΩ |
| | | V _{GS} = - 4.5 V, I _D = - 2 A | | 74 | | |
| Forward Transconductanceb | 9 _{fs} | V _{DS} = - 15 V, I _D = - 5 A | | 8 | | S |
| Dynamic | • | • | | • | | |
| Input Capacitance | C _{iss} | | | 1300 | | pF |
| Output Capacitance | C _{oss} | $V_{DS} = -25 V$, $V_{GS} = 0 V$, $f = 1 MHz$ | | 120 | | |
| Reverse Transfer Capacitance | C _{rss} | | | 90 | | |
| Total Gate Charge | Qg | $\frac{Q_{g}}{Q_{gs}} V_{DS} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -8.4 \text{ A}$ | 13 | | | |
| Gate-Source Charge | Q _{gs} | | | 2.3 | | nC |
| Gate-Drain Charge | Q _{gd} | | | 3.2 | | |
| Gate Resistance | Rg | f = 1 MHz | | 8.0 | | Ω |
| Turn-On Delay Time ^c | t _{d(on)} | | | 5 | 10 | |
| Rise Time ^c | t _r | V_{DD} = - 30 V, R_L = 3.57 Ω | | 14 | 25 | ns |
| Turn-Off Delay Time ^c | t _{d(off)} | ${\rm I_D}\cong$ - 8.4 A, ${\rm V_{GEN}}$ = - 10 V, ${\rm R_G}$ = 2.5 Ω | | 15 | 25 | |
| Fall Time ^c | t _f | | | 7 | 12 | |
| Source-Drain Diode Ratings and Cha | racteristics | (T _C = 25 °C) ^b | | | | |
| Pulsed Current | I _{SM} | | | - 20 | | А |
| Forward Voltage ^b | V _{SD} | I _F = - 2 A, V _{GS} = 0 V | | - 0.9 | - 1.3 | V |
| Reverse Recovery Time | t _{rr} | I _F = - 8 A, di/dt = 100 A/μs | | 50 | 80 | ns |
| Reverse Recovery Time | Q _{rr} | $F = -0.7$, $u_0 u_1 = 100.70 \mu_5$ | | 80 | 120 | nC |

Notes:

a. Guaranteed by design, not subject to production testing.

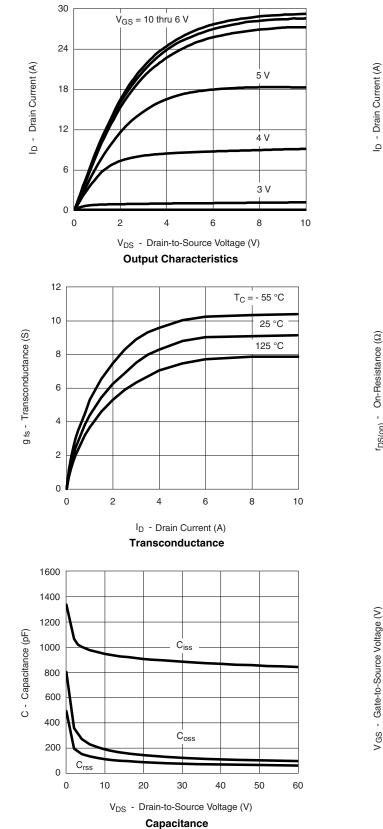
b. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

c. Independent of operating temperature.

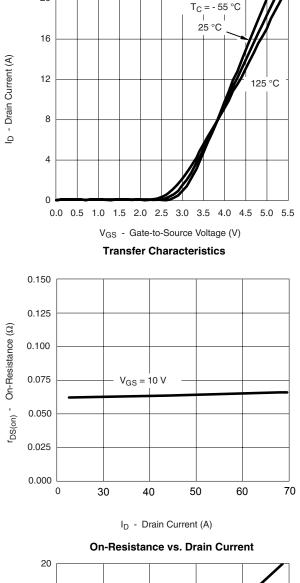
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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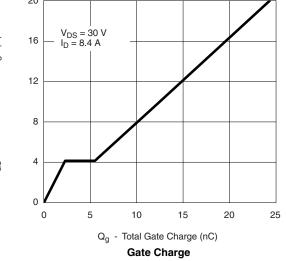




TYPICAL CHARACTERISTICS 25 °C unless noted

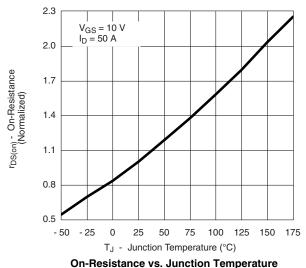


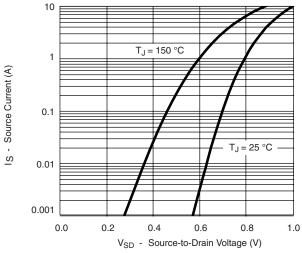
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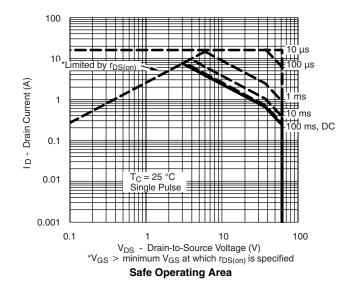


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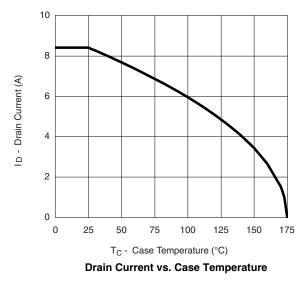




Source-Drain Diode Forward Voltage

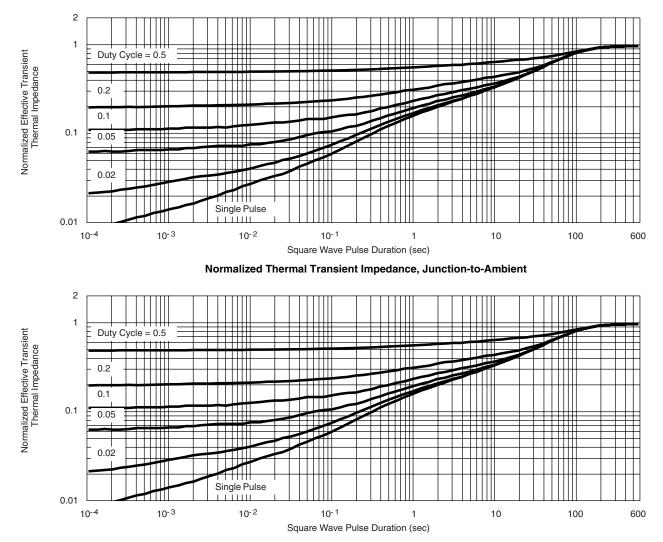


THERMAL RATINGS



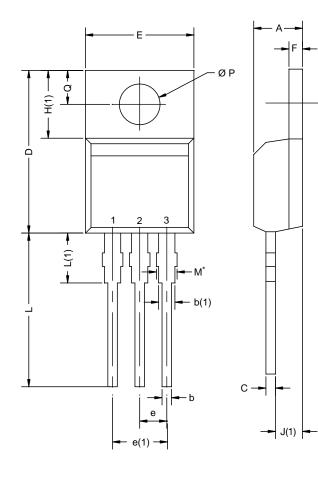


THERMAL RATINGS



Normalized Thermal Transient Impedance, Junction-to-Case





TO-220AB

| MIN. 4.25 0.69 | MAX. 4.65 | MIN. | MAX. |
|----------------------|---|---|---|
| - | 4.65 | 0.407 | |
| 0.69 | | 0.167 | 0.183 |
| | 1.01 | 0.027 | 0.040 |
| 1.20 | 1.73 | 0.047 | 0.068 |
| 0.36 | 0.61 | 0.014 | 0.024 |
| 14.85 | 15.49 | 0.585 | 0.610 |
| 10.04 | 10.51 | 0.395 | 0.414 |
| 2.41 | 2.67 | 0.095 | 0.105 |
| 4.88 | 5.28 | 0.192 | 0.208 |
| 1.14 | 1.40 | 0.045 | 0.055 |
| 6.09 | 6.48 | 0.240 | 0.255 |
| 2.41 | 2.92 | 0.095 | 0.115 |
| 13.35 | 14.02 | 0.526 | 0.552 |
| 3.32 | 3.82 | 0.131 | 0.150 |
| 3.54 | 3.94 | 0.139 | 0.155 |
| 2.60 | 3.00 | 0.102 | 0.118 |
| | 14.85 10.04 2.41 4.88 1.14 6.09 2.41 13.35 3.32 3.54 2.60 | 14.85 15.49 10.04 10.51 2.41 2.67 4.88 5.28 1.14 1.40 6.09 6.48 2.41 2.92 13.35 14.02 3.32 3.82 3.54 3.94 | 14.85 15.49 0.585 10.04 10.51 0.395 2.41 2.67 0.095 4.88 5.28 0.192 1.14 1.40 0.045 6.09 6.48 0.240 2.41 2.92 0.095 13.35 14.02 0.526 3.32 3.82 0.131 3.54 3.94 0.139 2.60 3.00 0.102 |

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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